Notice of References Cited Application/Control No. 10/617,106 Examiner Devona E. Faulk Applicant(s)/Patent Under Reexamination AISO ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,054,077	10-1991	Suzuki, Takashi	381/109
*	В	US-6,985,595	01-2006	Kohyama et al.	381/119
	C	US-			
	D	US-			
	Ε	US-			
	F	US-			
	O	US-			
	Η	US-			
	Т	US-			
	7	US-			
	K	US-			
	٦	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					,
	0			·		
	Р		·			
	Q	•				
	R					
	s					
	Т					Ť

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	w	
	×	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.